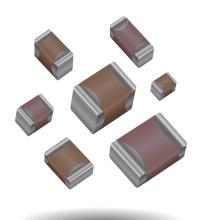
MLCC Medical Applications – MM Series

General Specifications





The AVX MM series is a multi-layer ceramic capacitor designed for use in medical applications other than implantable/life support. These components have the design & change control expected for medical devices and also offer enhanced LAT including reliability testing and 100% inspection.

APPLICATIONS

Implantable, Non-Life Supporting Medical Devices

· e.g. implanted temporary cardiac monitor, insulin pumps

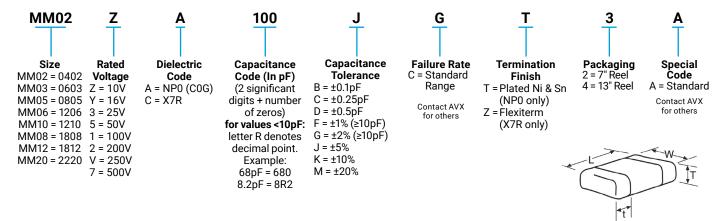
External, Life Supporting Medical Devices

· e.g. heart pump external controller

External Devices

· e.g. patient monitoring, diagnostic equipment

HOW TO ORDER



COMMERCIAL VS MM SERIES PROCESS COMPARISON

	Commercial	MM Series						
Administrative	Standard part numbers; no restriction on who purchases these parts	Specific series part number, used to control supply of product						
Design	Minimum ceramic thickness of 0.020" on all X7R product	Minimum ceramic thickness of 0.029" (0.74mm)						
Dicing	Side & end margins = 0.003" min	Side & end margins = 0.004" min Cover layers = 0.003" min						
Lot Qualification Destructive Physical Analysis (DPA)	As per EIA RS469	Increased sample plan – stricter criteria						
Visual/Cosmetic Quality	Standard process and inspection	100% inspection						
Application Robustness	Standard sampling for accelerated wave solder on X7R dielectrics	Increased sampling for accelerated wave solder on X7R and NP0 followed by lot by lot reliability testing						
Design/Change Control	Required to inform customer of changes in: form fit function	AVX will qualify and notify customers before making any change to the following materials or processes: • Dielectric formulation, type, or supplier • Metal formulation, type, or supplier • Termination material formulation, type, or supplier • Manufacturing equipment type • Quality testing regime including sample size and accept/ reject criteria						







Parame	ter/Test	NP0 Specification Limits	Measuring (Conditions						
	perature Range	-55°C to +125°C	Temperature C							
Capac	itance	Within specified tolerance	Freq.: 1.0 MHz ± 10%	% for cap ≤ 1000 pF						
(2	<30 pF: Q≥ 400+20 x Cap Value ≥30 pF: Q≥ 1000	1.0 kHz ± 10% fo Voltage: 1.0	Vrms ± .2V						
Dielectric Strength Appearance Capacitance Variation Plexure Stresses Q Insulation Resistance Solderability		100,000MΩ or 1000MΩ - μF, whichever is less	Charge device with rated voltage for 60 ± 5 secs @ room temp/humidity							
Dielectric	: Strength	No breakdown or visual defects	Charge device with 300% of rated voltage for 1-5 seconds, w/charge and discharge current limited to 50 mA (max) Note: Charge device with 150% of rated voltage for 500V devices.							
	Appearance	No defects	Deflectio	n: 2mm						
Resistance to		±5% or ±.5 pF, whichever is greater	Test Time: 3							
	Q									
		≥ Initial Value x 0.3	90 r							
Solder		≥ 95% of each terminal should be covered with fresh solder	Dip device in eutectic for 5.0 ± 0.5							
	Appearance	No defects, <25% leaching of either end terminal								
	Capacitance Variation	≤ ±2.5% or ±.25 pF, whichever is greater								
Resistance to Solder Heat	Q	Meets Initial Values (As Above)	Dip device in eutectic solder at 260°C for 60 seconds. Store at room temperature for 24 ± 2 hours before measuring electrical properties.							
	Insulation Resistance	Meets Initial Values (As Above)								
	Dielectric Strength	Meets Initial Values (As Above)								
	Appearance	No visual defects	Step 1: -55°C ± 2°	30 ± 3 minutes						
	Capacitance Variation	≤ ±2.5% or ±.25 pF, whichever is greater	Step 2: Room Temp	≤ 3 minutes						
Thermal Shock	Q	Meets Initial Values (As Above)	Step 3: +125°C ± 2°	30 ± 3 minutes						
Giloun	Insulation Resistance	Meets Initial Values (As Above)	Step 4: Room Temp ≤ 3 minutes Repeat for 5 cycles and measure after 24 hours at room temperature							
	Dielectric Strength	Meets Initial Values (As Above)								
	Appearance	No visual defects								
	Capacitance Variation	≤ ±3.0% or ± .3 pF, whichever is greater	Charge device with twic	ce rated voltage in test						
Load Life	Q	≥ 30 pF: Q≥ 350 ≥10 pF, <30 pF: Q≥ 275 +5C/2 <10 pF: Q≥ 200 +10C	for 1000 hou Remove from test cha	ırs (+48, -0).						
	Insulation Resistance	≥ Initial Value x 0.3 (See Above)	room test cha room temperatu before me	re for 24 hours						
	Dielectric Strength	Meets Initial Values (As Above)	Scioic IIIC							
	Appearance	No visual defects								
	Capacitance Variation	≤ ±5.0% or ± .5 pF, whichever is greater	Store in a test chamber							
Load Humidity	Q	≥ 30 pF: Q≥ 350 ≥10 pF, <30 pF: Q≥ 275 +5C/2 <10 pF: Q≥ 200 +10C	± 5% relative humid (+48, -0) with rated Remove from cham	d voltage applied.						
	Insulation Resistance	≥ Initial Value x 0.3 (See Above)	room temperature for measu	24 ± 2 hours before						
	Dielectric Strength	Meets Initial Values (As Above)								







PREFERRED SIZES ARE SHADED

SIZI			06	03				0805			1206								
	WVDC	16	25	50	100	16	25	50	100	16	25	50	100						
Cap 0.5	0R5																		
(pF) 1.0	1R0																		
1.2																			
1.5	1R5																		
1.8	1R8																		
2.2	2R2																		
2.7	2.17																		
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8.2																			
10	100																		
12	120																		
15	150																		
18																			
22	220																		
27	270																		
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39	390											-							
47	470																		
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100	101																		
120	121																		
150	151																		
180	181																		
220	221																		
270	271																		
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820	821																		
1000	102																		
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WVD		16	25	50	100	16	25	50	100	16	25	50	100						
SIZI				03				0805			1206								





Parame	ter/Test	X7R Specification Limits	Measuring Conditions									
	perature Range	-55°C to +125°C	Temperature C	ycle Chamber								
Capac	Q	Within specified tolerance ≤ 10% for ≥ 50V DC rating ≤ 12.5% for 25V DC rating ≤ 12.5% for 25V and 16V DC rating ≤ 12.5% for ≤ 10V DC rating	Freq.: 1.0 k Voltage: 1.0	:Hz ± 10% Vrms ± .2V								
Insulation	Resistance	100,000MΩ or 1000MΩ - μF, whichever is less	Charge device with rated voltage for 120 ± secs @ room temp/humidity									
Dielectric	: Strength	No breakdown or visual defects	Charge device with 300% of rated voltage for 1-5 seconds, w/charge and discharge current limited to 50 mA (max) Note: Charge device with 150% of rated voltage for 500V devices.									
	Appearance	No defects	Deflectio	n: 2mm								
Resistance to	Capacitance Variation	≤ ±12%	Test Time: 3									
Flexure Stresses	Dissipation Factor	Meets Initial Values (As Above)										
Insulation Resistance		≥ Initial Value x 0.3	90 r	mm —								
Solder		≥ 95% of each terminal should be covered with fresh solder	Dip device in eutectic for 5.0 ± 0.9									
	Appearance	No defects, <25% leaching of either end terminal										
	Capacitance Variation	≤ ±7.5%										
Resistance to Solder Heat	Dissipation Factor	Meets Initial Values (As Above)	Dip device in eutectic s seconds. Store at room	temperature for 24 ± 2								
Solder Heat	Insulation Resistance	Meets Initial Values (As Above)	hours before measuring	g electrical properties.								
	Dielectric Strength	Meets Initial Values (As Above)										
	Appearance	No visual defects	Step 1: -55°C ± 2°	30 ± 3 minutes								
	Variation	≤ ±7.5%	Step 2: Room Temp	≤ 3 minutes								
Thermal Shock	Factor	Meets Initial Values (As Above)	Step 3: +125°C ± 2°	30 ± 3 minutes								
5.1.03.1	Insulation Resistance	Meets Initial Values (As Above)	Step 4: Room Temp	≤ 3 minutes								
	Dielectric Strength	Meets Initial Values (As Above)	Repeat for 5 cycles 24 ± 2 hours at ro									
	Appearance	No visual defects										
	Variation	≤ ±12.5%	Charge device with 1.5 r test chamber set	at 125°C ± 2°C								
Load Life	Dissipation Factor	≤ Initial Value x 2.0 (See Above)	for 1000 hours (+48, -0)									
	Appearance Capacitance Variation Dissipation Factor Insulation Resistance Solderability Appearance Appearance Capacitance Variation Solderability Appearance Capacitance Variation Dissipation Factor Insulation Resistance Variation Dissipation Factor Insulation Resistance Dielectric Strength Appearance Capacitance Variation Appearance Appearance Dielectric Strength Appearance Capacitance Variation Dissipation Resistance Variation Meets Initial Values (As Above Insulated Values (As Above Insulation Insulation Insulation Insulation Resistance Variation Dissipation Factor Insulation Resistance Dielectric Strength Appearance Appearance Appearance Dielectric Strength Appearance Appearance Appearance Appearance Appearance Variation Dissipation Factor Insulation Resistance Variation Dissipation Factor Appearance Appearance Variation Dissipation Factor Appearance Variation Dissipation Factor Appearance No visual defects ≤ ±12.5% Dissipation Factor Selectric Strength Appearance No visual defects ≤ ±12.5% Dissipation Factor Selectric Strength Appearance No visual defects ≤ ±12.5% Dissipation Factor Selectric Strength Appearance No visual defects ≥ Initial Value x 0.3 (See Above)	Remove from test cha room temperature for	24 ± 2 hours before									
		Meets Initial Values (As Above)	meası	лту. 								
		No visual defects										
		≤ ±12.5%	Store in a test chamber ± 5% relative humid									
Load		≤ Initial Value x 2.0 (See Above)	(+48, -0) with rated									
Humidity	Insulation Resistance	≥ Initial Value x 0.3 (See Above)	Remove from chamber temperature an	d humidity for								
	Dielectric Strength	Meets Initial Values (As Above)	24 ± 2 hours before measuring.									







PREFERRED SIZES ARE SHADED

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Mouser Electronics

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